

THAPAR INSTITUTE

OF ENGINEERING & TECHNOLOGY

(Deemed-to-be-University u/s 3 of the UGC Act, 1956)

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Enquiry No.TIET/CS/AG/17-18/17487

Date: Feb 12, 2018

Sub: Request for Quotation(s) for the supply of Optical Microscope

Dear Sir

We shall be grateful if you kindly let us have your lowest quotations for the following materials. THE QUOTATIONS SHOULD REACH THE UNDERSIGNED LATEST BY 19.02.2018 through courier or e-mail accompanied by appropriate illustrative literature/catalogues/pamphlets/technical details, samples and specifications as the case may be. On the quotation envelope/ subject the Enquiry Number & Date should be mentioned on the top of the Envelope/mail subject.

Sr. No.	Item Name	Qty.
1.	Optical Microscope with Metallography Image Analyzer Software Specification List Attached:	1 Nos.

The offer sent by you must furnish the following details:

1. Name, Make & specifications of each item.
2. Cost of the item with MRP.(Treat it mandatory)
3. Educational discount if any.
4. Validity of quotation should be at least 60 Days.
5. GST . %
6. Delivery FOR Thapar University, Patiala
7. Insurance, Freight & other charges if any.
8. Minimum Delivery Period.
9. Payment terms. Net 30 days against delivery & satisfactory installation at Thapar Inst Of Engg & Tech .
10. Guarantee / Warranty Information.

Regards,

Sd/-

Head Commercial

Specification for Optical Microscope with Metallography Image Analyzer software

Specification for Optical Microscope

Objectives: Plan M-10X, Plan M-20X, Plan M-40X,
100X (Oil)
Eyepieces: Widefield WF-10X
Magnification Range: 100X - 1000X (standard)
Mechanical Stage: Co- axial mechanical square stage (200mm x 152mm)
revolving changer for perfect alignment

Metallography Image Analysis Software

Phase Analysis: As per ASTM E562 Quantifies volume % like Graphite, Pearlite, Ferrite, Martensite, Retained Austenite, carbide, Porosity etc..
Grain size : As per ASTM E112 Standard methods like Planimetric, Heyn Intercept, Hillard/Abrams circle intercept and manual grain analysis ALA grain size (ASTM E930) analysis Inclusion rating measurement as per ASTM E45 Standard
Dendrite Arm Spacing for Aluminium
Particle size analysis, Coating Thickness
Nodules: Nodularity Percentage, nodule count and graphite size
Graphite Flakes: Maximum flake length measurement
Measurements: like length, area, radius, distance
Report Generation: Exports to MS Office Excel
Camera: 3.1 MP CMOS